

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/724,169	PARK ET AL.	
Examiner	Art Unit	
Tianjie Chen	2627	

SEARCHED					
Class	Subclass	Date	Examiner		
720	650				
360	97.01				
361	749				
369	116				
200	305	6/16/2006	TJ		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East Reports	5/16/2006	TJ		
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